

ABSTRACT OF THE DISCLOSURE

A system for de-embedding electrical characteristics to obtain the intrinsic electrical characteristics of a device under test. The system includes obtaining a set of S parameter data from measurements of a thru test structure and partitioning that set into a set of input S parameters and a set of output S parameters. The set of input S parameters and the set of output S parameters are converted to sets of input ABCD parameters and output ABCD parameters, respectively. An inverse matrix of the set of input ABCD parameters is cascaded with a matrix of a set of ABCD parameters representative of the electrical characteristics of a test structure including the device under test. The resultant matrix is then cascaded with the inverse matrix of the set of output ABCD parameters to obtain a set of device ABCD parameters representative of the intrinsic electrical characteristics of the device under test.